

SLLIMM[™]-nano 2nd series IPM, 3-phase inverter, 3 A, 1.6 Ω max., 600 V N-channel MDmesh[™] DM2

Datasheet - production data



Features

- IPM 3 A, 600 V, R_{DS(on)} = 1.6 Ω, 3-phase MOSFET inverter bridge including control ICs for gate driving
- Optimized for low electromagnetic interference
- 3.3 V, 5 V, 15 V CMOS/TTL input comparators with hysteresis and pull-down/pull-up resistors
- Undervoltage lockout
- Internal bootstrap diode
- Interlocking function
- Smart shutdown function
- Comparator for fault protection against overtemperature and overcurrent
- Op-amp for advanced current sensing
- Optimized pinout for easy board layout
- NTC for temperature control (UL 1434 CA 2 and 4)
- Isolation ratings of 1500 Vrms/min.
- UL recognition: UL 1557 file E81734

Applications

- 3-phase inverters for motor drives
- Dish washers, refrigerator compressors, heating systems, air-conditioning fans, draining and recirculation pumps

Description

This SLLIMM (small low-loss intelligent molded module) nano provides a compact, high performance AC motor drive in a simple, rugged design. It is composed of six N-channel MDmesh DM2 MOSFETs with intrinsic fast recovery diode and three half-bridge HVICs for gate driving, providing low electromagnetic interference (EMI) characteristics with optimized switching speed. The package is designed to allow a better and easy screw on heatsink. It is optimized for thermal performance and compactness in built-in motor applications, or other low power applications where assembly space is limited. This IPM includes an operational amplifier, completely uncommitted, and a comparator that can be used to design a fast and efficient protection circuit. SLLIMM™ is a trademark of STMicroelectronics.

Table 1: Device summary

Order code	Marking	Package	Packing
STIPQ3M60T-HL	IPQ3M60T-HL	N2DIP-26L type L	Tube
STIPQ3M60T-HZ	IPQ3M60T-HZ	N2DIP-26L type Z	Tube

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DocID030240 Rev 2

1/25

This is information on a product in full production.

Contents

1	Internal	schematic diagram and pin configuration	3
2	Electric	al ratings	5
	2.1	Absolute maximum ratings	5
	2.2	Thermal data	5
3	Electric	al characteristics	6
	3.1	Inverter part	6
	3.2	Control part	
		3.2.1 NTC thermistor	10
	3.3	Waveform definitions	13
4	Smart s	shutdown function	14
5	Applica	tion circuit example	16
	5.1	Guidelines	17
6	Package	e information	19
	6.1	N2DIP-26L type L package information	19
	6.2	N2DIP-26L type Z package information	
	6.3	N2DIP-26L packing information	
7	Revisio	n history	



1 Internal schematic diagram and pin configuration



Figure 1: Internal schematic diagram



Pin	Symbol	Table 2: Pin description Description
1	GND	Ground
2	T/SD/OD	NTC thermistor terminal / shutdown logic input (active low) / open-drain (comparator output)
3	Vcc W	Low voltage power supply W phase
4	HIN W	High-side logic input for W phase
5	LIN W	Low-side logic input for W phase
6	OP+	Op-amp non inverting input
7	OPOUT	Op-amp output
8	OP-	Op-amp inverting input
9	Vcc V	Low voltage power supply V phase
10	HIN V	High-side logic input for V phase
11	LIN V	Low-side logic input for V phase
12	CIN	Comparator input
13	Vcc U	Low voltage power supply for U phase
14	HIN U	High-side logic input for U phase
15	T/SD/OD	NTC thermistor terminal / shutdown logic input (active low) / open-drain (comparator output)
16	LIN U	Low-side logic input for U phase
17	V _{BOOT} U	Bootstrap voltage for U phase
18	Р	Positive DC input
19	U, OUTu	U phase output
20	Nu	Negative DC input for U phase
21	V _{BOOT} V	Bootstrap voltage for V phase
22	V,OUT_V	V phase output
23	Nv	Negative DC input for V phase
24	VBOOT W	Bootstrap voltage for W phase
25	W, OUT _W	W phase output

57

2 Electrical ratings

2.1 Absolute maximum ratings

Symbol	Parameter	Value	Unit
V _{DSS}	MOSFET blocking voltage (or drain-source voltage) for each MOSFET ($V_{IN}^{(1)}=0$)	600	V
± lo	Continuous current each MOSFET	3	Α
± I _{DP} ⁽²⁾	Peak drain current each MOSFET (less than 1 ms)	6	Α
P _{TOT}	Each MOSFET total dissipation at T_C = 25 °C	11.7	W

Notes:

⁽¹⁾Applied among HINi, LINi and GND for i = U, V, W.

 $\ensuremath{^{(2)}}\ensuremath{\mathsf{Pulse}}$ width limited by max. junction temperature.

Symbol	Parameter	Min.	Max.	Unit
V _{OUT}	Output voltage applied among OUT _U , OUT _V , OUT _V , OUT _W - GND	V _{boot} - 21	V _{boot} + 0.3	V
Vcc	Low voltage power supply	- 0.3	21	V
V _{CIN}	Comparator input voltage	- 0.3	V _{CC} + 0.3	V
V _{op+}	Op-amp non-inverting input	- 0.3	Vcc + 0.3	V
V _{op-}	Op-amp inverting input	- 0.3	Vcc + 0.3	V
V _{boot}	Bootstrap voltage	- 0.3	620	V
Vin	Logic input voltage applied among HIN, LIN and GND	- 0.3	15	V
$V_{T/\overline{SD}/OD}$	Open-drain voltage	- 0.3	15	V
$\Delta V_{OUT/dT}$	Allowed output slew rate		50	V/ns

Table 4: Control part

Table 5: Total system

Symbol	Parameter	Value	Unit
V _{ISO}	Isolation withstand voltage applied on each pin and heatsink plate (AC voltage, $t = 60 s$)	1500	V
Tj	Power chip operating junction temperature range	-40 to 150	°C
Tc	Module case operation temperature range	-40 to 125	°C

2.2 Thermal data

Table 6: Thermal data

Symbol	Parameter	Value	Unit
Rth(j-c)	Thermal resistance junction-case single MOSFET	10.7	°C/W



3 Electrical characteristics

 $T_J = 25$ °C unless otherwise specified.

3.1 Inverter part

Table 7: Static						
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
IDSS	Zero-gate voltage drain current	$V_{DS} = 600 \text{ V}, \text{ V}_{CC} = 15 \text{ V},$ $V_{boot} = 15 \text{ V}$			1	mA
V _{(BR)DSS}	Drain-source breakdown voltage	$\label{eq:Vcc} \begin{split} V_{CC} = V_{boot} = 15 \ V, \ V_{IN}{}^{(1)} = 0 \ V, \\ I_D = 1 \ mA \end{split}$	600			V
R _{DS(on)}	Static drain source turn-on resistance	$V_{CC} = V_{boot} = 15 V,$ $V_{IN}^{(1)} = 0 - 5 V, I_D = 1.5 A$		1.35	1.6	Ω
V _{SD}	Drain-source diode forward voltage	$V_{IN}^{(1)} = 0$ "logic state", $I_D = 3 \text{ A}$		1.4	1.9	V

Notes:

⁽¹⁾Applied among HINx, LINx and GND for x = U, V, W.

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit	
ton ⁽¹⁾	Turn-on time		-	220	-		
t _{c(on)} (1)	Crossover time (on)	V _{DD} = 300 V,	-	72	-		
t _{off} ⁽¹⁾	Turn-off time	$V_{CC} = V_{boot} = 15 V,$	-	225	-	ns	
t _{c(off)} ⁽¹⁾	Crossover time (off)	$V_{IN}^{(2)} = 0 - 5 V,$ Ic = 1.2 A	-	29	-		
trr	Reverse recovery time	(see Figure 3: "Switching time	-	79	-		
Eon	Turn-on switching energy	definition")	-	47	-	1	
Eoff	Turn-off switching energy		-	3.9	-	μJ	

Table 8: Inductive load switching time and energy

Notes:

 $^{(1)}\text{ton}$ and toFF include the propagation delay time of the internal drive. $t_{C(ON)}$ and $t_{C(OFF)}$ are the switching time of MOSFET itself under the internally given gate driving conditions.

 $^{(2)}\mbox{Applied}$ among HINx, LINx and GND for x = U, V, W.



Electrical characteristics



Figure 3: Switching time definition







3.2 Control part

Table 9: Low voltage power supply (Vcc = 15 V unless otherwise specified)

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
Vcc_hys	Vcc UV hysteresis		1.2	1.5	1.8	V
V _{CC_thON}	V _{CC} UV turn-ON threshold		11.5	12	12.5	V
Vcc_thOFF	Vcc UV turn-OFF threshold		10	10.5	11	V
I _{qccu}	Undervoltage quiescent supply current	$V_{CC} = 10 \text{ V}, \text{ T/}\overline{\text{SD}}/\text{OD} = 5 \text{ V};$ LIN = 0 V; H _{IN} = 0, C _{IN} = 0			150	μA
I _{qcc}	Quiescent current	$V_{cc} = 15 \text{ V}, \text{ T/SD}/\text{OD} = 5 \text{ V};$ LIN = 0 V; H _{IN} = 0, C _{IN} = 0			1	mA
Vref	Internal comparator (CIN) reference voltage		0.5	0.54	0.58	V

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V_{BS_hys}	V _{BS} UV hysteresis		1.2	1.5	1.8	V
VBS_thON	VBS UV turn-ON threshold		11.1	11.5	12.1	V
$V_{\text{BS_thOFF}}$	VBS UV turn-OFF threshold		9.8	10	10.6	V
Ιαβου	Undervoltage V _{BS} quiescent current	$\label{eq:VBS} \begin{array}{l} V_{BS} < 9 \ V \ T/\overline{SD}/OD = 5 \ V; \\ LIN = 0 \ V \ and \ HIN = 5 \ V; \\ C_{IN} = 0 \end{array}$		70	110	μA
IQBS	V _{BS} quiescent current	$\label{eq:VBS} \begin{array}{l} V_{BS} = 15 \text{ V T/SD}/\text{OD} = 5 \text{ V};\\ \text{LIN} = 0 \text{ V and HIN} = 5 \text{ V};\\ \text{C}_{\text{IN}} = 0 \end{array}$		200	300	μA
R _{DS(on)}	Bootstrap driver on- resistance	LVG ON		120		Ω

Table 11: Logic inputs (V_{CC} = 15 V unless otherwise specified)

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
Vil	Low logic level voltage				0.8	V
Vih	High logic level voltage		2.25			V
I HINh	HIN logic "1" input bias current	HIN = 15 V	20	40	100	μA
Ihini	HIN logic "0" input bias current	HIN = 0 V			1	μA
Ilini	LIN logic "1" input bias current	LIN = 15 V	20	40	100	μA
ILINh	LIN logic "0" input bias current	LIN = 0 V			1	μA
Isdh	SD logic "0" input bias current	<u>SD</u> = 15 V	220	295	370	μA
Isdi	SD logic "1" input bias current	$\overline{\text{SD}} = 0 \text{ V}$			3	μA
Dt	Dead time	see Figure 8: "Dead time and interlocking waveform definitions"		180		ns



Electrical characteristics

	Table 12: Op-amp characteristics (Vcc = 15 V unless otherwise specified)						
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit	
Vio	Input offset voltage	$V_{ic} = 0 \ V, \ V_o = 7.5 \ V$			6	mV	
lio	Input offset current			4	40	nA	
lib	Input bias current (1)	$V_{ic} = 0 V, V_o = 7.5 V$		100	200	nA	
Vol	Low level output voltage	R_L = 10 k Ω to V _{CC}		75	150	mV	
V _{OH}	High level output voltage	R_L = 10 k Ω to GND	14	14.7		V	
		Source, $V_{id} = +1 V$; $V_o = 0 V$	16	30		mA	
lo	Output short-circuit current	Sink, $V_{id} = -1 V$; $V_o = V_{CC}$	50	80		mA	
SR	Slew rate	$V_i = 1 - 4 V;$ $C_L = 100 \text{ pF};$ unity gain	2.5	3.8		V/µs	
GBWP	Gain bandwidth product	V _o = 7.5 V	8	12		MHz	
A _{vd}	Large signal voltage gain	R _L = 2 kΩ	70	85		dB	
SVR	Supply voltage rejection ratio	vs. V _{CC}	60	75		dB	
CMRR	Common mode rejection ratio		55	70		dB	

Notes:

⁽¹⁾The direction of the input current is out of the IC.

Tak	Table 13: Sense comparator characteristics (V_{CC} = 15 V unless otherwise specified)							
ymbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit		

Symbol	Parameter Test conditions Mi		Min.	Тур.	Max.	Unit
l _{ib}	Input bias current	V _{CIN} = 1 V			3	μA
V _{od}	Open-drain low level output voltage	l _{od} = 3 mA			0.5	V
RON_OD	Open-drain low level output resistance	l _{od} = 3 mA		166		Ω
R _{PD_SD}	<u>SD</u> pull-down resistor ⁽¹⁾			125		kΩ
t _{d_comp}	Comparator delay	T/SD/OD pulled to 5 V through 100 k Ω resistor		90	130	ns
SR	Slew rate	$C_L = 180 \text{ pF}; R_{pu} = 5 \text{ k}\Omega$		60		V/µs
t _{sd}	Shutdown to high / low-side driver propagation delay	$V_{OUT} = 0, V_{boot} = V_{CC},$ $V_{IN} = 0 \text{ to } 3.3 \text{ V}$	50	125	200	
t _{isd}	Comparator triggering to high / low-side driver turn-off propagation delay	Measured applying a voltage step from 0 V to 3.3 V to pin CIN	50	200	250	ns

Notes:

 $\ensuremath{^{(1)}}\xspace$ Equivalent values are as the result of the resistances of three drivers in parallel.



Electrical characteristics

STIPQ3M60T-HL, STIPQ3M60T-HZ

Conditions	Log	Logic input (V)			Output	
Conditions	T/SD/OD	LIN	HIN	LVG	HVG	
Shutdown enable half-bridge tri-state	L	X ⁽¹⁾	X ⁽¹⁾	L	L	
Interlocking half-bridge tri-state	Н	Н	Н	L	L	
0 "logic state" half-bridge tri-state	Н	L	L	L	L	
1 "logic state" low-side direct driving	Н	Н	L	Н	L	
1 "logic state" high-side direct driving	Н	L	Н	L	Н	

Table 14. Truth table

Notes:

⁽¹⁾X: do not care.

3.2.1 **NTC thermistor**



RPD_SD: equivalent value as result of resistances of three drivers in parallel.



Electrical characteristics



Figure 6: Equivalent resistance (NTC//RPD_SD) zoom



57

Electrical characteristics

STIPQ3M60T-HL, STIPQ3M60T-HZ



Figure 7: Voltage of T/SD/OD pin according to NTC temperature

3.3 Waveform definitions



Figure 8: Dead time and interlocking waveform definitions



4 Smart shutdown function

The device integrates a comparator for fault sensing purposes. The comparator has an internal voltage reference V_{REF} connected to the inverting input, while the non-inverting input on pin (CIN) can be connected to an external shunt resistor for overcurrent protection.

When the comparator triggers, the device is set to the shutdown state and both of its outputs are set to low level, causing the half- bridge to enter a tri-state.

In common overcurrent protection architectures, the comparator output is usually connected to the shutdown input through an RC network so to provide a mono-stable circuit which implements a protection time following to fault condition.

Our smart shutdown architecture immediately turns off the output gate driver in case of overcurrent through a preferential path for the fault signal which directly switches off the outputs. The time delay between the fault and output shutdown no longer depends on the RC values of the external network connected to the shutdown pin. At the same time, the DMOS connected to the open-drain output (pin T/SD/OD) is turned on by the internal logic, which holds it on until the shutdown voltage is well below the minimum value of logic input threshold (Vil).

Besides, the smart shutdown function allows the real disable time to be increased without rising the constant time of the external RC network.

NTC thermistor for temperature monitoring is internally connected in parallel to the \overline{SD} pin. To avoid undesired shutdown, keep the voltage $V_{T/\overline{SD}/OD}$ higher than the high level logic threshold by setting the pull-up resistor $R_{\overline{SD}}$ to 1 k Ω or 2.2 k Ω for 3.3 V or 5 V MCU power supplies, respectively.





Please refer to *Table 13:* "Sense comparator characteristics ($V_{CC} = 15$ V unless otherwise specified)" for internal propagation delay time details.



5 Application circuit example



Application designers are free to use a different scheme according to the specifications of the device.

DocID030240 Rev 2



5.1 Guidelines

- Input signals HIN, LIN are active high logic. A 375 k Ω (typ.) pull-down resistor is builtin for each input. To prevent input signal oscillations, the wiring of each input should be as short as possible and the use of RC filters (R₁, C₁) on each input signal is suggested. The filters should be with a time constant of about 100 ns and placed as close as possible to the IPM input pins.
- The use of a bypass capacitor CVCC (aluminum or tantalum) helps to reduce the transient circuit demand on the power supply. Furthermore, to reduce high frequency switching noise distributed on the power lines, a decoupling capacitor C₂ (100 to 220 nF, with low ESR and low ESL) should be placed as close as possible to Vcc pin and in parallel with the bypass capacitor.
- The use of RC filter (RSF, CSF) is recommended to prevent protection circuit malfunction. The time constant (RSF x CSF) should be set to 1 µs and the filter must be placed as close as possible to the CIN pin.
- The \overline{SD} is an input/output pin (open-drain type if used as output). A built-in thermistor NTC is internally connected between the \overline{SD} pin and GND. The voltage VSD-GND decreases as the temperature increases, due to the pull-up resistor RSD. In order to keep the voltage always higher than the high level logic threshold, the pull-up resistor has to be set to 1 k Ω or 2.2 k Ω for 3.3 V or 5 V MCU power supply, respectively. The CSD capacitor of the filter on \overline{SD} should be fixed no higher than 3.3 nF in order to assure \overline{SD} activation time $\tau_1 < = 500$ ns and the filter should be placed as close as possible to the \overline{SD} pin.
- The decoupling capacitor C₃ (from 100 to 220 nF, ceramic with low ESR and low ESL), in parallel with each C_{boot}, filters high frequency disturbance. Both C_{boot} and C3 (if present) should be placed as close as possible to the U, V, W and V_{boot} pins. Bootstrap negative electrodes should be connected to U, V, W terminals directly and separated from the main output wires.
- To prevent the overvoltage on Vcc pin, a Zener diode (Dz1) can be used. Similarly on the V_{boot} pin, a Zener diode (Dz2) can be placed in parallel with each C_{boot}.
- The use of the decoupling capacitor C₄ (100 to 220 nF, with low ESR and low ESL) in parallel with the electrolytic capacitor C_{vdc} prevents surge destruction. Both capacitors C₄ and Cvdc should be placed as close as possible to the IPM (C4 has priority over C_{vdc}).
- By integrating an application-specific type HVIC inside the module, direct coupling to the MCU terminals without an optocoupler is possible.
- Low inductance shunt resistors for phase leg current sensing have to be used.
- In order to avoid malfunctions, the wiring on N pins, the shunt resistor and PWR_GND should be as short as possible.
- The connection of SGN_GND to PWR_GND to the point only (close to the shunt resistor terminal) reduces the impact of power ground fluctuation.

These guidelines ensure the specifications of the device for application designs. For further details, please refer to the relevant application note.



Application circuit example

STIPQ3M60T-HL, STIPQ3M60T-HZ

	Table 15: Recommended operating conditions						
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit	
V _{PN}	Supply voltage	Applied among P-Nu, Nv, Nw		300	500	V	
Vcc	Control supply voltage	Applied to Vcc-GND	13.5	15	18	V	
V _{BS}	High-side bias voltage	Applied to V_{BOOTi} -OUT _i for i = U, V, W	13		18	V	
t _{dead}	Blanking time to prevent arm- short	For each input signal	1			μs	
fрwм	PWM input signal	-40 °C < T _c < 100 °C -40 °C < T _j < 125 °C			25	kHz	
Tc	Case operation temperature				100	°C	



6 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK[®] packages, depending on their level of environmental compliance. ECOPACK[®] specifications, grade definitions and product status are available at: *www.st.com*. ECOPACK[®] is an ST trademark.

6.1 N2DIP-26L type L package information







Package information

STIPQ3M60T-HL, STIPQ3M60T-HZ chanical data

nformation	STIPQ3M601-HL, STIPQ3M601-HZ						
	Table 16: N2DIP-26L type L mechanical data						
Dim.		mm					
Dim.	Min.	Тур.	Max.				
A	4.80	5.10	5.40				
A1	0.80	1.00	1.20				
A2	4.00	4.10	4.20				
A3	1.70	1.80	1.90				
A4	1.70	1.80	1.90				
A5	8.10	8.40	8.70				
A6	1.75						
b	0.53		0.72				
b2	0.83		1.02				
С	0.46		0.59				
D	32.05	32.15	32.25				
D1	2.10						
D2	1.85						
D3	30.65	30.75	30.85				
Е	12.35	12.45	12.55				
е	1.70	1.80	1.90				
e1	2.40	2.50	2.60				
eB1	14.25	14.55	14.85				
L	0.85	1.05	1.25				
Dia	3.10	3.20	3.30				



6.2 N2DIP-26L type Z package information

Figure 12: N2DIP-26L type Z package outline





Package information

STIPQ3M60T-HL, STIPQ3M60T-HZ

nformation		STIPQ3M60T-HL, STIPQ3M60T-HZ				
Table 17: N2DIP-26L type Z mechanical data						
Dim.		mm				
Dim.	Min.	Тур.	Max.			
A	4.80	5.10	5.40			
A1	0.80	1.00	1.20			
A2	4.00	4.10	4.20			
A3	1.70	1.80	1.90			
A4	1.70	1.80	1.90			
A5	8.10	8.40	8.70			
A6	1.75					
b	0.53		0.72			
b2	0.83		1.02			
С	0.46		0.59			
D	32.05	32.15	32.25			
D1	2.10					
D2	1.85					
D3	30.65	30.75	30.85			
E	12.35	12.45	12.55			
е	1.70	1.80	1.90			
e1	2.40	2.50	2.60			
eB1	16.10	16.40	16.70			
eB2	21.18	21.48	21.78			
L	0.85	1.05	1.25			
Dia	3.10	3.20	3.30			



6.3 N2DIP-26L packing information

Figure 13: N2DIP-26L tube (dimensions are in mm)



57

7 Revision history

Table 18: Document revision history

Date	Revision	Changes
17-Jan-2017	1	Initial release.
27-Jun-2017	2	Document status promoted from preliminary data to production data. Updated features in cover page. Minor text changes.



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